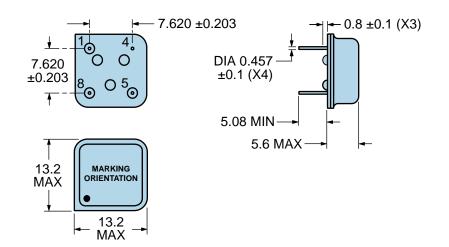


| ELECTRICAL SPECIFICAT | TIONS | |
|---------------------------------------|--|--|
| Nominal Frequency | 8.192MHz | |
| Frequency Tolerance/Stability | ±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range, Supply Voltage Change, Ouput Load Change, 1st Year Aging at 25°C, Shock, and Vibration.) | |
| Aging at 25°C | ±5ppm/year Maximum | |
| Operating Temperature Range | 0°C to +70°C | |
| Supply Voltage | 3.3Vdc ±0.3Vdc | |
| Input Current | 35mA Maximum (No Load) | |
| Output Voltage Logic High (Voh) | 2.7Vdc Minimum (IOH = -8mA) | |
| Output Voltage Logic Low (Vol) | 0.5Vdc Maximum (IOL = +8mA) | |
| Rise/Fall Time | 6nSec Maximum (Measured at 20% to 80% of waveform) | |
| Duty Cycle | 50 ±5(%) (Measured at 50% of waveform) | |
| Load Drive Capability | 30pF Maximum | |
| Output Logic Type | CMOS | |
| Pin 1 Connection | Tri-State (Disabled Output: High Impedance) | |
| Tri-State Input Voltage (Vih and Vil) | 70% of Vdd Minimum to enable output, 20% of Vdd Maximum to disable output (High Impedance), No Connect to enable output. | |
| Absolute Clock Jitter | ±250pSec Maximum, ±100pSec Typical | |
| One Sigma Clock Period Jitter | ±50pSec Maximum, ±40pSec Typical | |
| Start Up Time | 10mSec Maximum | |
| Storage Temperature Range | -55°C to +125°C | |

| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS | | |
|---|---------------------------------------|--|
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A | |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C | |
| Lead Integrity | MIL-STD-883, Method 2004 | |
| Mechanical Shock | MIL-STD-202, Method 213, Condition C | |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 | |
| Resistance to Solvents | MIL-STD-202, Method 215 | |
| Solderability | MIL-STD-883, Method 2003 | |
| Temperature Cycling | MIL-STD-883, Method 1010 | |
| Vibration | MIL-STD-883, Method 2007, Condition A | |



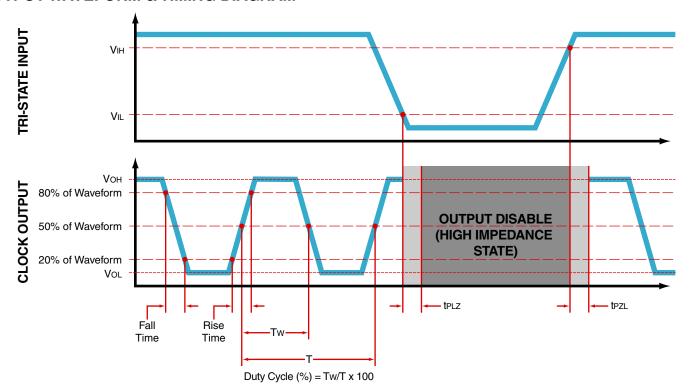
MECHANICAL DIMENSIONS (all dimensions in millimeters)



| PIN | CONNECTION |
|-----|----------------------------|
| 1 | Tri-State (High Impedance) |
| 4 | Case/Ground |
| 5 | Output |
| 8 | Supply Voltage |

| LINE | MARKING |
|------|---|
| 1 | ECLIPTEK |
| 2 | EH13TS EH13=Product Series |
| 3 | 8.192M |
| 4 | XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year |

OUTPUT WAVEFORM & TIMING DIAGRAM





Test Circuit for CMOS Output



Note 1: An external $0.1\mu\text{F}$ low frequency tantalum bypass capacitor in parallel with a $0.01\mu\text{F}$ high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods



High Temperature Solder Bath (Wave Solder)

| T _S MAX to T _L (Ramp-up Rate) | 3°C/second Maximum |
|---|--------------------------------------|
| Preheat | |
| - Temperature Minimum (T _s MIN) | 150°C |
| - Temperature Typical (T _s TYP) | 175°C |
| - Temperature Maximum (T _s MAX) | 200°C |
| - Time (t _s MIN) | 60 - 180 Seconds |
| Ramp-up Rate (T _L to T _P) | 3°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T∟) | 217°C |
| - Time (t∟) | 60 - 150 Seconds |
| Peak Temperature (T _P) | 260°C Maximum for 10 Seconds Maximum |
| Target Peak Temperature (T _P Target) | 250°C +0/-5°C |
| Time within 5°C of actual peak (tp) | 20 - 40 seconds |
| Ramp-down Rate | 6°C/second Maximum |
| Time 25°C to Peak Temperature (t) | 8 minutes Maximum |
| Moisture Sensitivity Level | Level 1 |



Recommended Solder Reflow Methods

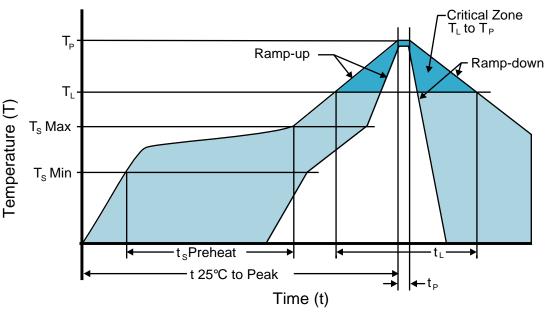


Low Temperature Infrared/Convection 185°C

| T _S MAX to T _L (Ramp-up Rate) | 5°C/second Maximum |
|---|----------------------------|
| Preheat | |
| - Temperature Minimum (T _s MIN) | N/A |
| - Temperature Typical (T _s TYP) | 150°C |
| - Temperature Maximum (T _s MAX) | N/A |
| - Time (ts MIN) | 60 - 120 Seconds |
| Ramp-up Rate (T _L to T _P) | 5°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T∟) | 150°C |
| - Time (t∟) | 200 Seconds Maximum |
| Peak Temperature (T _P) | 185°C Maximum |
| Target Peak Temperature (T _P Target) | 185°C Maximum 2 Times |
| Time within 5°C of actual peak (tp) | 10 seconds Maximum 2 Times |
| Ramp-down Rate | 5°C/second Maximum |
| Time 25°C to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |



Recommended Solder Reflow Methods



Low Temperature Solder Bath (Wave Solder)

| T _s MAX to T _L (Ramp-up Rate) | 5°C/second Maximum |
|---|---|
| Preheat | |
| - Temperature Minimum (T _s MIN) | N/A |
| - Temperature Typical (T _s TYP) | 150°C |
| - Temperature Maximum (T _s MAX) | N/A |
| - Time (t _s MIN) | 30 - 60 Seconds |
| Ramp-up Rate (T _L to T _P) | 5°C/second Maximum |
| Time Maintained Above: | |
| - Temperature (T _L) | 150°C |
| - Time (t∟) | 200 Seconds Maximum |
| Peak Temperature (T _P) | 245°C Maximum |
| Target Peak Temperature (T _P Target) | 245°C Maximum 1 Time / 235°C Maximum 2 Times |
| Time within 5°C of actual peak (tp) | 5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times |
| Ramp-down Rate | 5°C/second Maximum |
| Time 25°C to Peak Temperature (t) | N/A |
| Moisture Sensitivity Level | Level 1 |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum.

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum.